

## N-Channel Power MOSFET (63A, 55Volts)

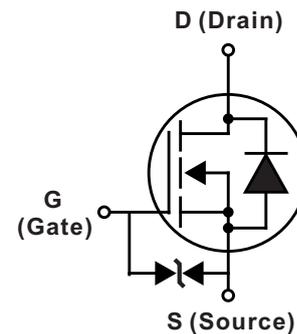
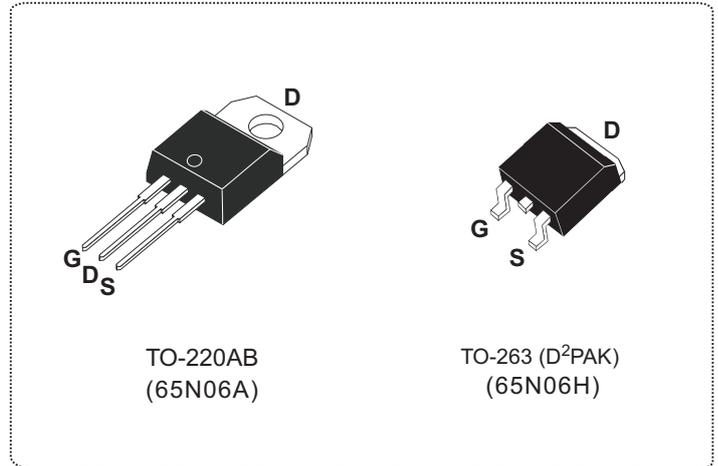
### DESCRIPTION

The Nell **65N06** is a three-terminal silicon device with current conduction capability of 63A, fast switching speed, low on-state resistance, breakdown voltage rating of 55V, and max. threshold voltage of 4 volts.

They are designed as an extremely efficient and reliable device and has integral zener giving diodes ESD protection up to 2KV. They are intended for use in DC to DC convertors and general purpose switching applications.

### FEATURES

- $R_{DS(ON)} = 18m\Omega @ V_{GS} = 10V$
- Ultra low gate charge(40nC typical)
- Low reverse transfer capacitance ( $C_{RSS} = 170pF$  typical)
- Fast switching capability
- 100% avalanche energy specified
- Improved dv/dt capability
- 175°C operation temperature



PRODUCT SUMMARY	
$I_D$ (A)	63
$V_{DSS}$ (V)	60
$R_{DS(ON)}$ ( $\Omega$ )	0.018 @ $V_{GS} = 10V$
$Q_G$ (nC) typ.	40

ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ C$ unless otherwise specified)				
SYMBOL	PARAMETER	TEST CONDITIONS	VALUE	UNIT
$V_{DSS}$	Drain to Source voltag	$T_J = 25^\circ C$ to $150^\circ C$	55	V
$V_{DGR}$	Drain to Gate voltage	$R_{GS} = 20K\Omega$	55	
$V_{GS}$	Gate to Source voltage		$\pm 20$	
$I_D$	Continous Drain Current	$V_{GS} = 10V, T_C = 25^\circ C$	63	A
		$V_{GS} = 10V, T_C = 100^\circ C$	44	
$I_{DM}$	Pulsed Drain current(Note 1)		240	
dv/dt	Peak diode recovery dv/dt(Note 2)		7.0	V/ns
$P_D$	Total power dissipation	$T_C = 25^\circ C$	150	W
	Derating factor above $25^\circ C$		1.0	W/ $^\circ C$
$V_C$	Electro-static Discharge capacitor voltage, all pins	Human body model (100 pF, 1.5K $\Omega$ )	2	KV
$T_J$	Operation junction temperature		-55 to 175	$^\circ C$
$T_{STG}$	Storage temperature		-55 to 175	
$T_L$	Maximum soldering temperature, for 10 seconds	1.6mm from case	300	
	Mounting torque, #6-32 or M3 screw		10 (1.1)	lbf-in (N·m)

Note: 1. Repetitive rating; pulse width limited by junction temperature.  
2.  $I_{SD} \leq 50A, di/dt \leq 300A/\mu s, V_{DD} \leq V_{(BR)DSS}$ , starting  $T_J = 25^\circ C$ .

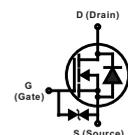
## Nell High Power Products

THERMAL RESISTANCE					
SYMBOL	PARAMETER	Min.	Typ.	Max.	UNIT
$R_{th(j-c)}$	Thermal resistance, junction to case			1.05	
$R_{th(c-s)}$	Thermal resistance, case to heatsink		0.50		°C/W
$R_{th(j-a)}$	Thermal resistance, junction to ambient			62.5	

### ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ unless otherwise specified)

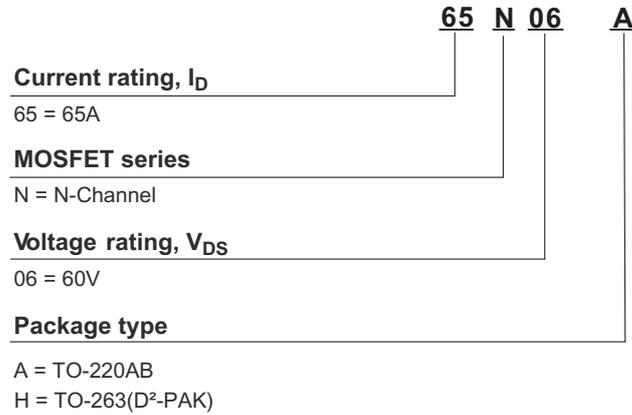
SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
$V_{(BR)DSS}$	Drain to source breakdown voltage	$V_{GS}=0V, I_D=250\mu A$	55			V
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown voltage temperature coefficient	$I_D = 250\mu A$ , referenced to $25^\circ\text{C}$		0.07		V/°C
$I_{DSS}$	Drain to source leakage current	$V_{DS}=60V, V_{GS}=0V$	$T_C = 25^\circ\text{C}$		5	$\mu A$
			$T_C = 150^\circ\text{C}$		250	
$I_{GSS}$	Gate to source forward leakage current	$V_{GS} = -20V, V_{DS} = 0V$			100	nA
	Gate to source reverse leakage current	$V_{GS} = 20V, V_{DS} = 0V$			-100	
$R_{DS(ON)}$	Static drain to source on-state resistance	$V_{GS}=10V, I_D=25A$ (Note 1)		15	18	mΩ
$V_{GS(TH)}$	Gate threshold voltage	$V_{GS}=V_{DS}, I_D=1000\mu A$	2		4	V
$g_{fs}$	Forward transconductance	$V_{DS}=25V, I_D=25A$	6	30		
$C_{ISS}$	Input capacitance	$V_{DS} = 25V, V_{GS} = 0V, f = 1\text{MHz}$		1500	2000	pF
$C_{OSS}$	Output capacitance			370	470	
$C_{RSS}$	Reverse transfer capacitance			170	250	
$t_{d(ON)}$	Turn-on delay time	$V_{DD} = 30V, I_D = 25A, R_G=10\Omega$ $V_{GS}=10V$ (Note 1)		15	25	ns
$t_r$	Rise time			30	60	
$t_{d(OFF)}$	Turn-off delay time			35	50	
$t_f$	Fall time			25	40	
$L_D$	Internal drain inductance	Between lead, 6mm form package and center of die		4.5		nH
$L_S$	Internal source inductance			7.5		
$Q_G$	Total gate charge	$V_{DS} = 44V, V_{GS} = 10V$ $I_D = 50A$		40		nC
$Q_{GS}$	Gate to source charge			10		
$Q_{GD}$	Gate to drain charge (Miller charge)			15		
$W_{DSS}$	Drain to source non-repetitivw unclamped inductive turn-off energy	$I_D = 50A, V_{DD}\leq 25V,$ $V_{GS}=10V, R_{GD}=50\Omega$			125	mJ

### SOURCE TO DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ unless otherwise specified)

SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
$V_{SD}$	Diode forward voltage	$I_{SD} = 25A, V_{GS} = 0V$		0.95	1.20	V
		$I_{SD} = 50A, V_{GS} = 0V$		1.0	1.35	
$I_S(I_{SD})$	Continuous source to drain current	Integral reverse P-N junction diode in the MOSFET			63	A
$I_{SM}$	Pulsed source current				240	
$t_{rr}$	Reverse recovery time	$I_{SD} = 50A, V_{GS} = -10V,$ $V_R=30V, dI_F/dt = -100A/\mu s$		50		ns
$Q_{rr}$	Reverse recovery charge				0.1	$\mu C$
$t_{ON}$	Forward turn-on time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

Note: 1. Pulse test: Pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$

## ORDERING INFORMATION SCHEME



## ■ TEST CIRCUITS AND WAVEFORMS

Fig.1A Peak diode recovery dv/dt test circuit

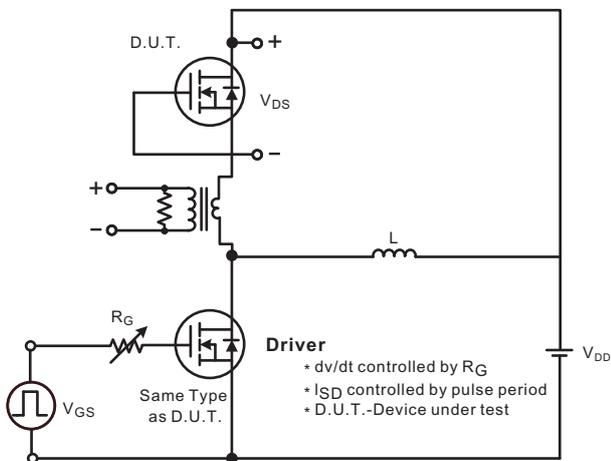
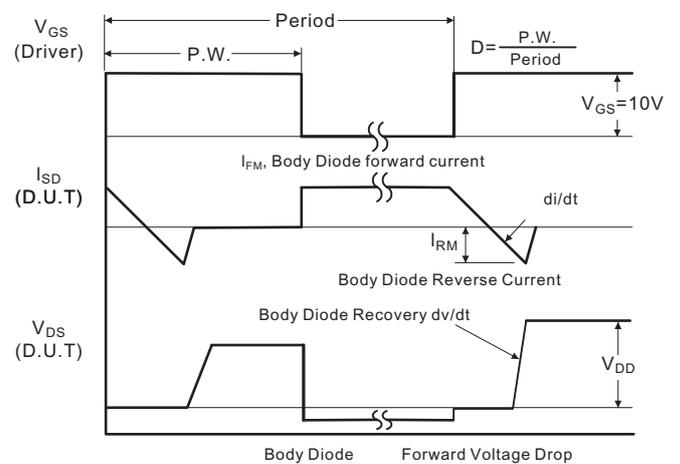
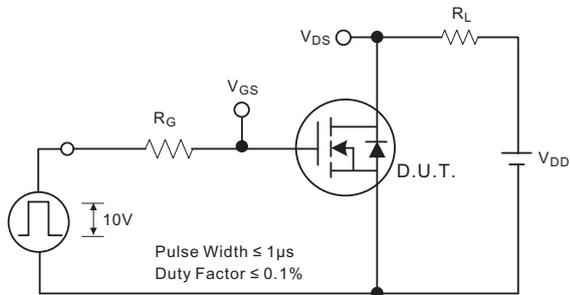


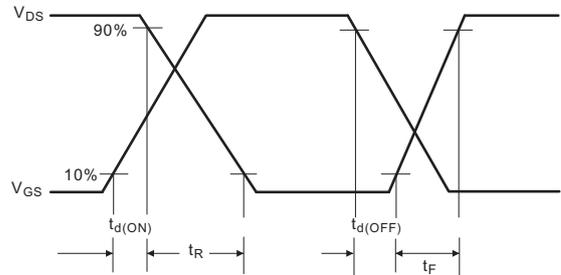
Fig.1B Peak diode recovery dv/dt waveforms



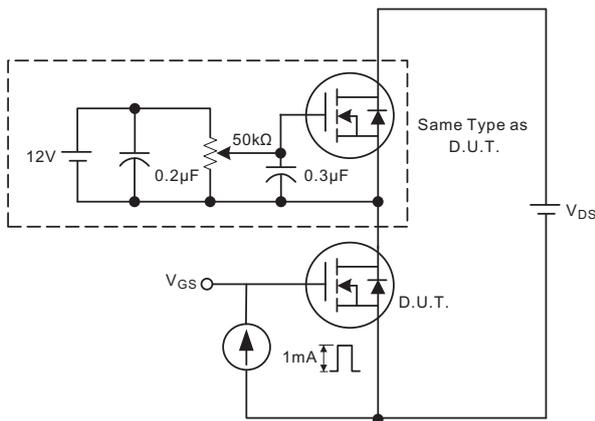
**Fig.2A Switching test circuit**



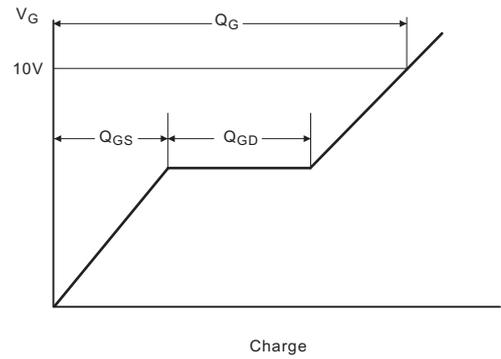
**Fig.2B Switching Waveforms**



**Fig.3A Gate charge test circuit**

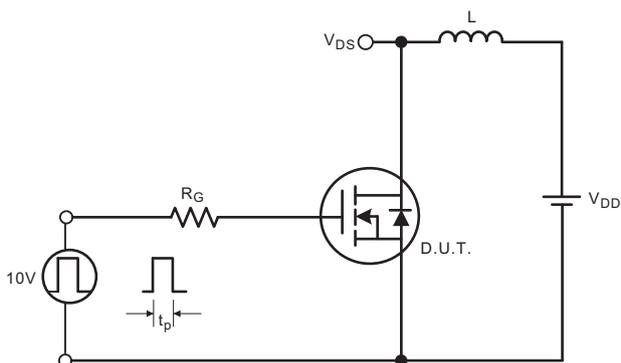


**Fig.3B Gate charge waveform**

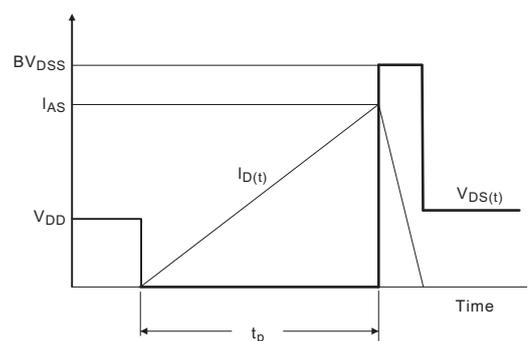


## ■ TEST CIRCUITS AND WAVEFORMS (Cont.)

**Fig.4A Unclamped Inductive switching test circuit**

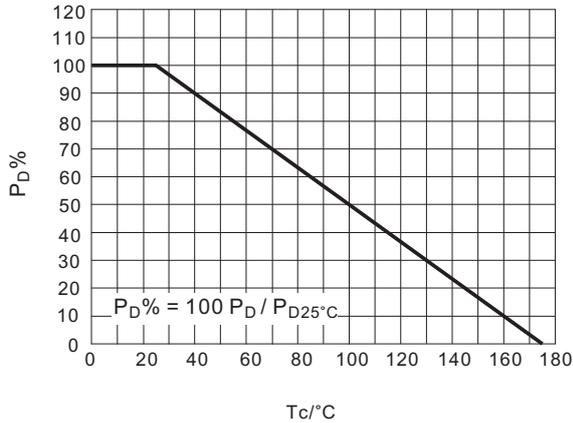


**Fig.4B Unclamped Inductive switching waveforms**

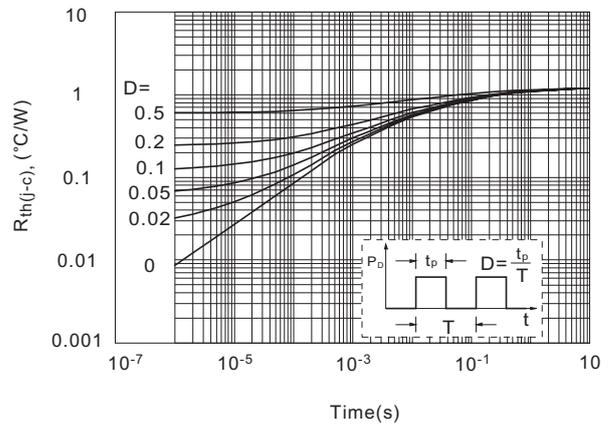


■ **TYPICAL CHARACTERISTICS**

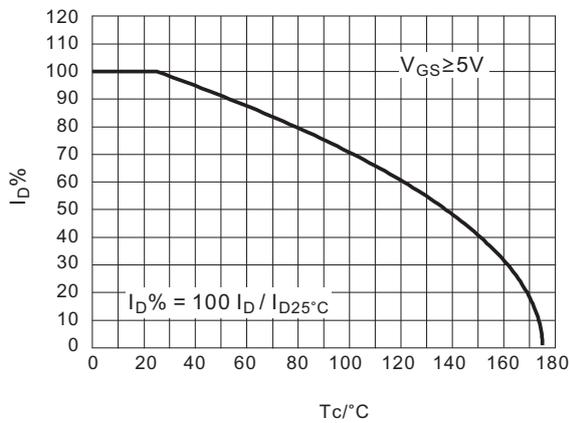
**Fig.1 Normalised power dissipation**



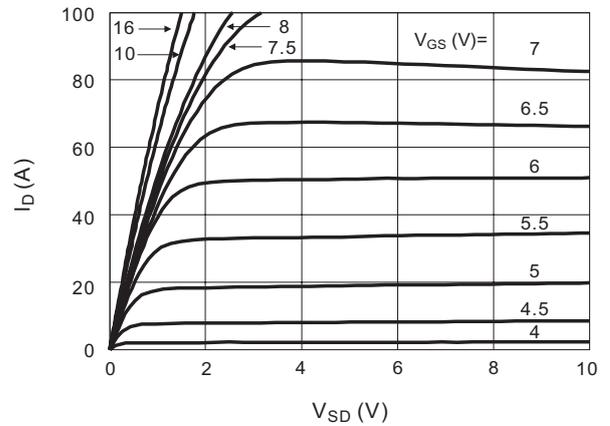
**Fig.2 Transient thermal impedance**



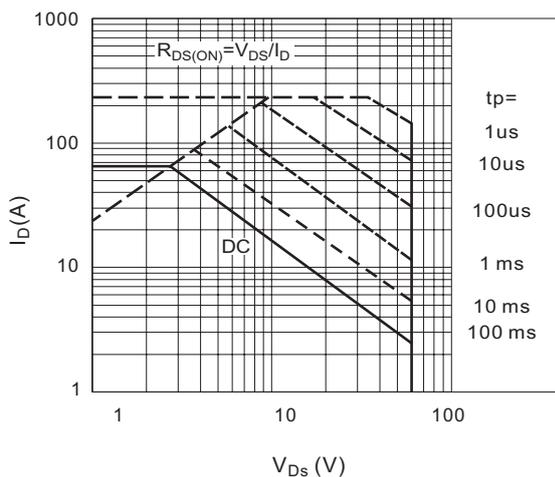
**Fig.3 Normalised continuous drain current**



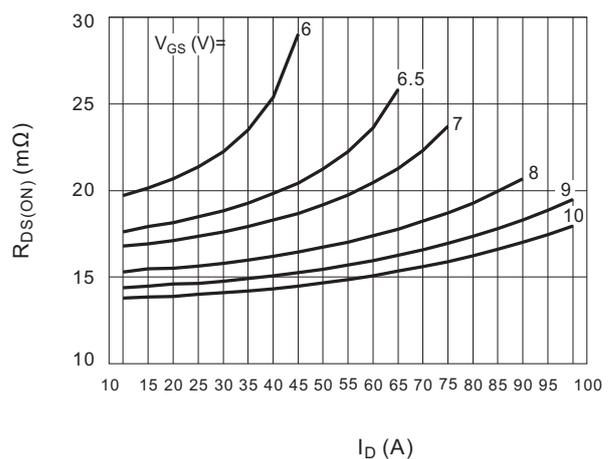
**Fig.4 Typical output characteristics, T\_j=25°C**



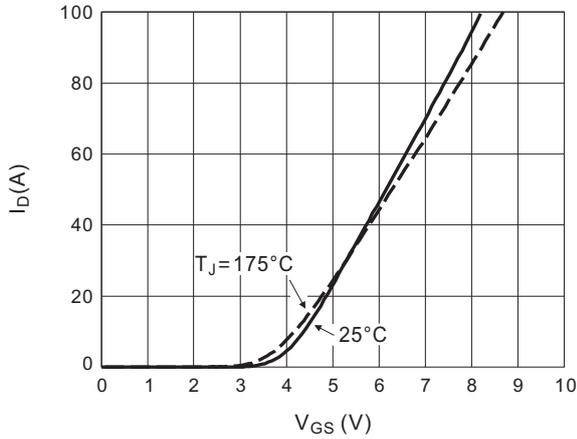
**Fig.5 Safe operating area. T\_{mb}=25°C**



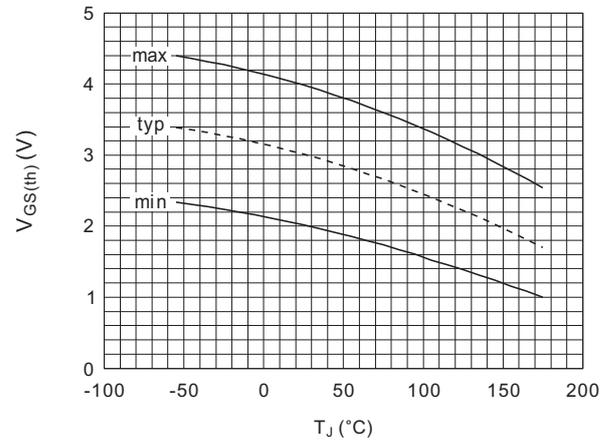
**Fig.6 Typical on-state resistance, T\_j=25°C**



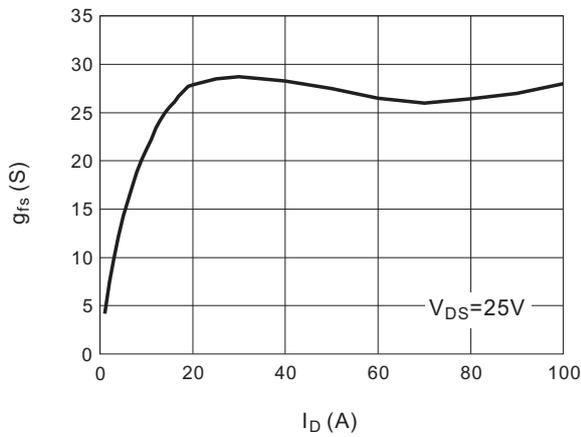
**Fig.7 Typical transfer characteristics**



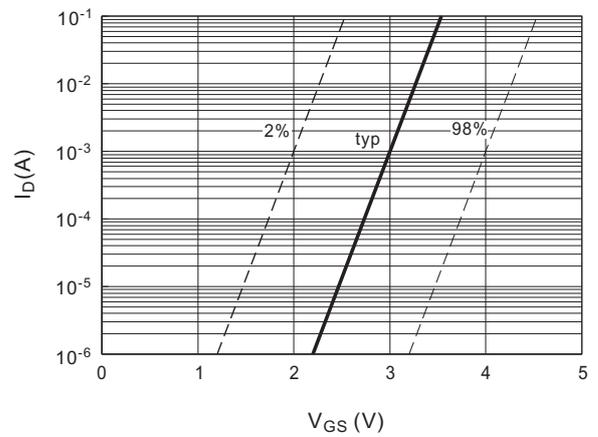
**Fig.8 Gate threshold voltage**



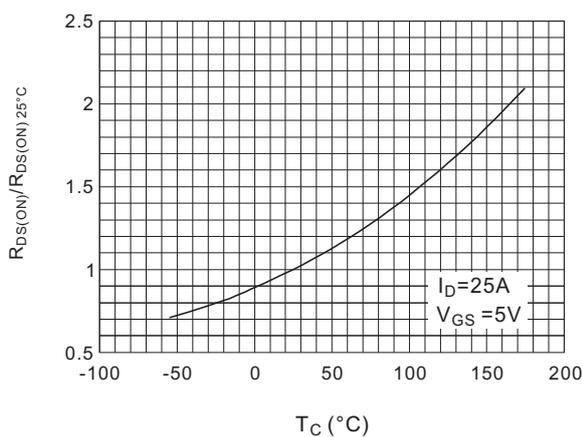
**Fig.9 Typical transconductance,  $T_J = 25^\circ\text{C}$**



**Fig.10 Sub-threshold drain current**



**Fig.11 Normalized drain-source on-state resistance**



**Fig.12 Typical capacitances,  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$**

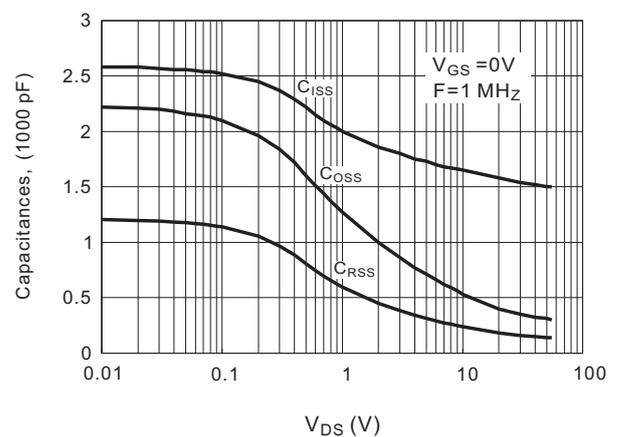


Fig. 13 Typical turn-on gate-charge characteristics

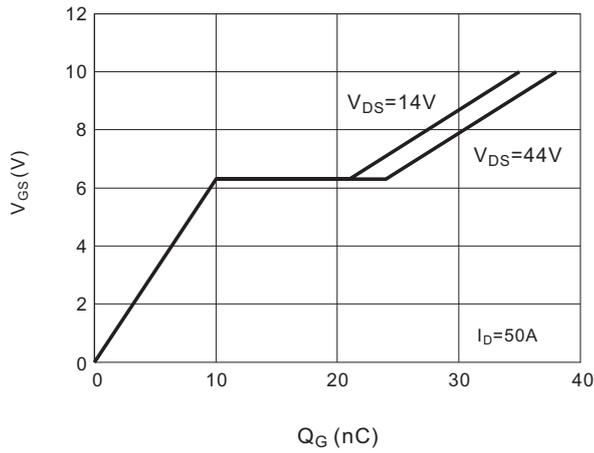


Fig. 14 Normalised avalanche energy rating

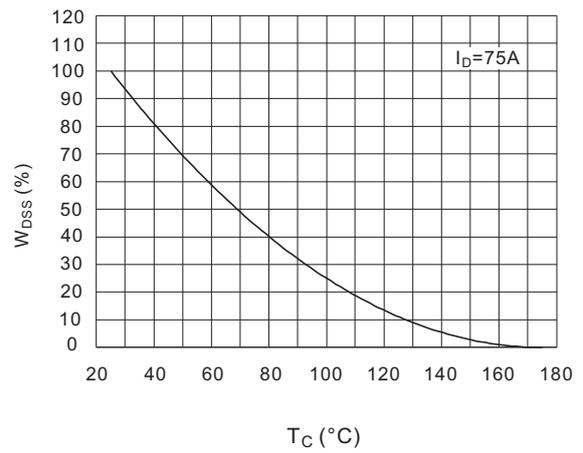


Fig. 15 Typical diode forward voltage

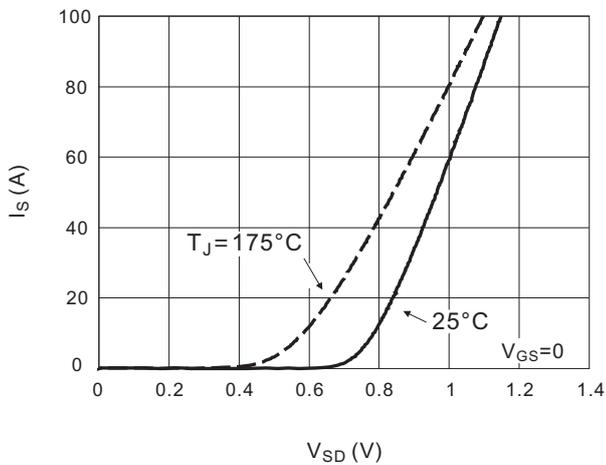
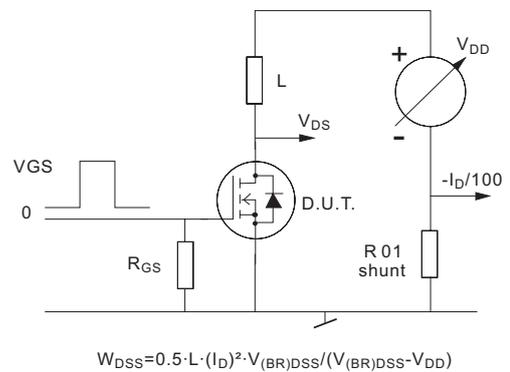
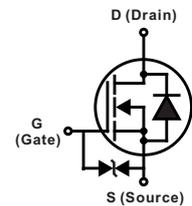
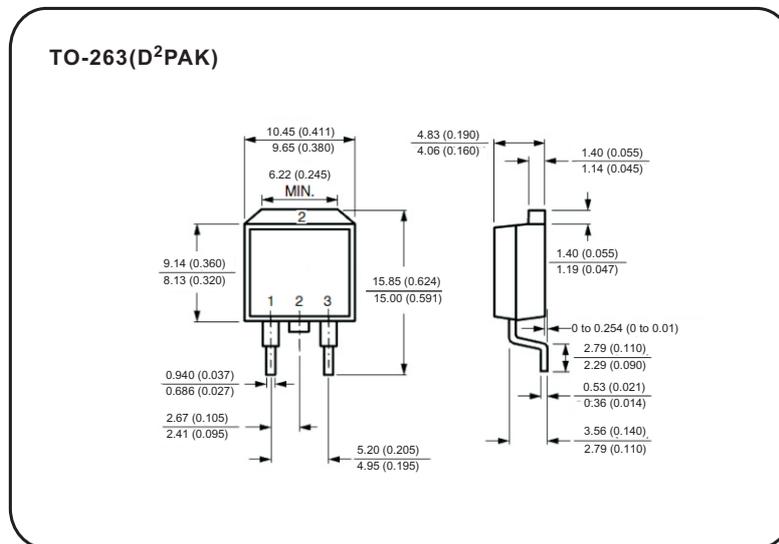
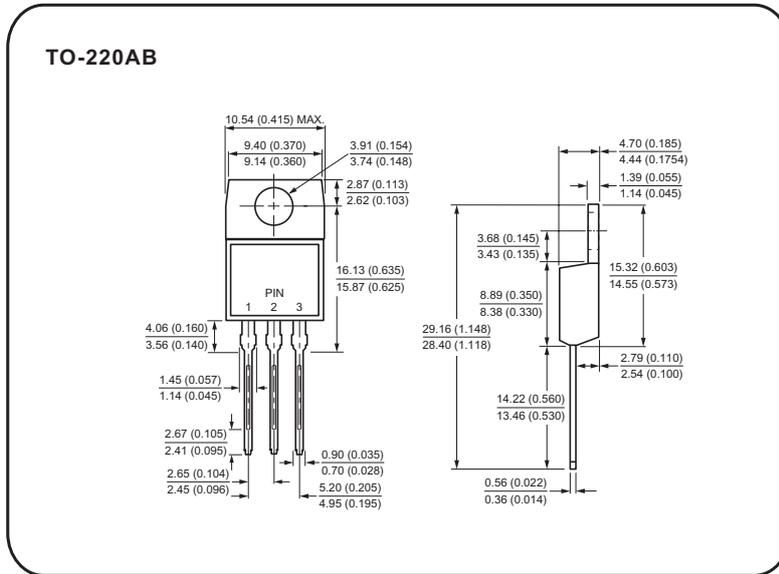


Fig. 16 Avalanche energy test circuit



### Case Style



All dimensions in millimeters(inches)